

Doc. No. : PCN211206 Date : Dec 30, 2021

To: Dear Valued Customers

Product/Process Change Notice

We hereby submit PCN for your review and approval.

Application or type :

Datasheet for (A)CDBQx0240LR-HF.

Detail of the change :

Modify the electrical characteristics of the datasheet.

Current : e.g. CDBQC0240LR-HF

Parameter	Conditions	Symbol	Min	Тур	Max	Unit
	IF = 10mA	VF			0.35	V
Forward voltage	IF = 100mA	VF			0.48	V
	IF = 200mA	VF			0.58	V
Reverse current	V _R = 10V	IR			0.5	μA
Reverse current	V _R = 40V	IR			5	μA
Capacitance	f = 1 MHz, and 1 VDC reverse voltage	Ст		12		pF

After the change : e.g. CDBQC0240LR-HF

Electrical Characteristics (at TA=25°C unless otherwise noted)							
Parameter Conditions Symbol Min Typ Max							
Forward voltage	l⊧ = 100mA	VF			0.48	V	
	Ir = 200mA	VF			0.58	V	
Reverse current	V _R = 40V	IR			5	μΑ	
Capacitance	f = 1MHz, and 1 VDC reverse voltage	Ст		25	35	pF	

Reason for the change :

Refer to the PCN210901 dated September 6, 2021 and the reliability test report dated September 1, 2021, modify the datasheet to ensure compliance with the electrical characteristics of the new Schottky wafer.

Evaluation items :

Part No.	Package Type
ACDBQC0240LR-HF	0402C/SOD-923F
CDBQC0240LR-HF	0402C/SOD-923F
CDBQR0240LR-HF	0402/SOD-923F

Implemented from :

Effective immediately.

R&D Dept. Signature :

QA Dept. Signature :

bein Tsong



Answer To PCN

Please complete the form below duly signed and fax back to Comchip Technology Co.

Please select your answer	Date					
1. Approved this PCN						
 Approved this PCN with conditions Disapproved this PCN 	Responsibility By					
5. Disappioved this i eiv						
Please specify the condition or explain the reason if you select 2 or 3.						
Trease specify the condition of explain the reason if you select 2 of 5.						

Unless a Comchip Technology Co., Ltd. Sales representative is contacted in writing within 30 days of the posting of this notice, all changes described in this announcement are considered approved.



Doc. No. : PCN210901 Date : Sep 6, 2021

To: Dear Valued Customers

Product/Process Change Notice

We hereby submit PCN for your review and approval.

Application or type : The schottky product add new wafer supplier. Detail of the change : Add new schottky product wafer supplier due to chip shortage. Current : After the change : Wafer: MD1BIP614010 Wafer : MT(D)1BIP611010 MD1BIP614020 MT(D)1BIP611000 Reason for the change : This notification is to advise our customers that we will add new wafer supplier of schottky products to better support long-term demand for the affected products. Full electrical characterization and high reliability testing have been completed to ensure that it meets specifications and then modify the datasheet according to the qualification results. Reliability reports as attached file. Evaluation items : Part No. CDBQC0130L-HF CDBUR0130L-HF ACDBQC0130L-HF CDBER0130L-HF CDBQC0240L-HF CDBUR0230L-HF CDBER0230L-HF CDBQR0130L-HF CDBURT0230L-HF CDBF0130L-HF CDBQR0230L-HF CDBQR0240LR-HF CDBF0230L-HF CDBU0130L-HF ACDBQC0240LR-HF CDBFR0130L-HF CDBU0230L-HF Implemented from : Mar 31, 2022



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R&D Dept. Signature :	QA Dept. Signature :
Zm	Veim Ten

Answer To PCN

Please complete the form below duly signed and fax back to Comchip Technology Co.

Please select your answer	Date
1. Approved this PCN	
2. Approved this PCN with conditions	Responsibility By
3. Disapproved this PCN	
Please specify the condition or explain the reason if you select 2 or	3.

Unless a Comchip Technology Co., Ltd. Sales representative is contacted in writing within 30 days of the posting of this notice, all changes described in this announcement are considered approved.



Reliability Test Report

Part NO.: Part No. affected Diodes

Doc. No. PCN210901

Date: 2021.09.01

ComChip Technology Co., Ltd.

Add. : No. 586, Jianguo Rd., Yingge Dist., New Taipei City 23943, Taiwan

Tel.: 886-2-8677-6675

QR-0803-02 Rev.G

Comchip Technology Co., Ltd.



Date: 2021/9/1

Reliability Test Summary

P / N : Part No. affected

Doc. No. : PCN210901

Application or type : The schottky product add new wafer supplier. Detail of the change : Add new schottky product wafer supplier due to chip shortage.

No	Test Item	Test Condition	Test Foundation	Failure qty'	S.S	Test Results
1	Solderability	Dip in flux Time=5sec. Temp.of solder Pot=245±5℃ Time= 5~10 sec.	MIL-STD-750 Method 2026	0	22	PASS
2	Soldering Heat	Temp of solder pot=260±5℃ Time= 10~12 sec	MIL-STD-750 Method 2031	0	22	PASS
3	Temperature Cycle	Low Tstg to High Tstg dwelled for 30 min and transfer time not exceed 1 min; 20 cycles	MIL-STD-750 Method 1051	0	22	PASS
4	Steady State Operation Life Test	I=lo mA Time=168hrs.	MIL-STD-750 Method 1027	0	22	PASS
5	High Temperature Reverse Bias Life	VR= VR*80% Temp.(depend on product) Time 168hrs.	MIL-STD-750 Method 1038	0	22	PASS
6	Intermittent Forward Operation Life	lf = lo mA ON 1.5hrs/OFF 0.5hrs Test Time : 84Cycles	MIL-STD-750 Method 1036	0	22	PASS
7	Pressure Cooker Test	Ta= 121℃ Pressure= 15 Psi Time= 4 hrs	JESD 22-A102	0	22	PASS
8	High Temperature Storage Life	Ta= High Tstg. Time= 168 hrs	MIL-STD-750 Method 1031	0	22	PASS
9	Humidity	Ta= 85 ℃ RH= 85% Time=168 hrs	EIAJ ED-4701	0	22	PASS

Conclusion:

1.共有9項實驗

2.測試結果:PASS

Approval: Zeus Lai

Prepare: Judy Lin



Reliability Test Report

Product.: Part No. affected

Doc. No. PCN210901

Date: 2021.09.01

ComChip Technology Co., Ltd.

Add. : No. 586, Jianguo Rd., Yingge Dist., New Taipei City 23943, Taiwan

Tel.: 886-2-8677-6675

QR-0803-02 Rev.G

Comchip Technology Co., Ltd.



Discrete Semiconductor Component Qualification Plan

 Supplier Intermal P / N :
 Part No. affected

 Supplier :
 Comchip

 Required PPAP Submission Date :
 2021/9/1

 User Component Engineer :
 Judy Lin

 General Specification :
 AEC-Q101 Rev-D

 Table 3: Process Change Guidelines for the Selection of Tests

 Supplier Manufacturing Site :
 Yingge, Taiwan

 Application or type :
 The schottky product add new wafer supplier.

Detail of the change: Add new schottky product wafer supplier due to chip shortage.

Item	Test	Test Conditions	Test Foundation	S. S.	Remarks
1	TEST	Electrical characterization @25C	SPEC.	572	PASS
2	Preconditioning	Ta= 125℃ Time= 24 hrs Ta= 85 ℃ RH= 85% Time = 168 hrs 3 reflow cycles	JESD22 A-113	308	PASS
3	External Visual	per AEC-Q101	SPEC.	572	PASS
4	HTRB	Reverse Biased @ 100% V Ta= Tj. Test Time=1000 hrs	MIL-STD-750 M1038 Method A	77	PASS
5	Temperature Cycling	Tamin = -55℃ to Tamax150℃ dwelled for 5 min, Cycle = 1000	JESD22 A-104	77	PASS
6	Autoclave	Ta = 121℃, P = 15psig, RH = 100% Test Time=96hrs	JESD22 A-102	77	PASS
7	H3TRB	Reverse Biased @ 80% V Ta= 85 °C, RH= 85% Test Time=1000 hrs	JESD22 A-101	- 77	PASS
7a	HAST	Reverse Biased @ 80% V Ta= 130 ℃, RH= 85% Test Time=96 hrs	JESD22 A-110		1 400
8	IOL	$\Delta TJ \ge 100^{\circ}C$, On/Off = 2 minutes, cvcles = 15.000	MIL-STD-750 Method 1037	77	PASS
9	HTSL	Ta= Ts℃. Time= 1000 hrs	JESD22 A-103	77	PASS
10	ESD	CDM HBM	AEC Q101-001 and 005	60	PASS
11	DPA	per AEC-Q101	AEC-Q101-004 Section 4	2	PASS

Comchip Technology Co., Ltd.



Discrete Semiconductor Component Qualification Plan

Supplier Intermal P / N : Part No. affected

Supplier : Comchip

User Component Engineer : Judy Lin

Required PPAP Submission Date : 2021/9/1 Doc. No. : PCN210901

General Specification : AEC-Q101 Rev-D Table 3: Process Change Guidelines for the Selection of Tests

Supplier Manufacturing Site : Yingge, Taiwan

Application or type: The schottky product add new wafer supplier.

Detail of the change : Add new schottky product wafer supplier due to chip shortage.

Item	Test	Test Conditions	Test Foundation	S. S.	Remarks
12	Physical Dimension	per AEC-Q101	JESD22 B-100	30	PASS
13	Resistance to Solder Heat	Solder Pot Temp. $260\pm5^{\circ}$ C Duration 4-6 sec	JESD22 A-111	30	PASS
14	Solderability	Solder Pot Temp. 245±5℃ Duration 5-10 sec	JESD22 B-102	10	PASS
15	Thermal Resistance	per AEC-Q101	JESD24-3, 24- 4, 24-6 as appropriate	10	PASS
16	Wire Bond Strength	per MIL-STD-750 Method 2037	MIL-STD-750 Method 2037	5	PASS
17	Bond Shear	per AEC-Q101-003	AEC-Q101-003	5	PASS
18	Die Shear	per MIL-STD-750 Method 2017	MIL-STD-750 Method 2017	5	PASS

Conclusion:

1. The total test had 18 item of reability test.

Notes:

7 & 7a choose one

2. There were test result of pass.

Approval: Zeus Lai

Prepare: Judy Lin